SCAS005B - JULY 1987 - REVISED APRIL 1993

- Flow-Through Architecture Optimizes PCB Layout
- Center-Pin V_{CC} and GND Configurations Minimize High-Speed Switching Noise
- *EPIC*[™] (Enhanced-Performance Implanted CMOS) 1-μm Process
- 500-mA Typical Latch-Up Immunity at 125°C
- Package Options Include Plastic Small-Outline Packages, Ceramic Chip Carriers, and Standard Plastic and Ceramic 300-mil DIPs

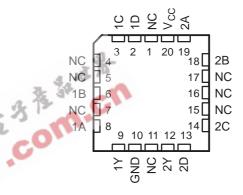
description

These devices contain two independent 4-input AND gates. They perform the Boolean functions $Y = A \cdot B \cdot C \cdot D$ or $Y = \overline{A} + \overline{B} + \overline{C} + \overline{D}$ in positive logic.

The 54AC11021 is characterized for operation over the full military temperature range of -55° C to 125°C. The 74AC11021 is characterized for operation from -40° C to 85°C.

54AC11021 J PACKAGE 74AC11021 D OR N PACKAGE (TOP VIEW)								
1B [1A [1Y [GND [2Y [2D] 2C [1 2 3 4 5 6 7	12 11 10	NC 1C 1D V _{CC} 2A 2B NC					

54AC11021 . . . FK PACKAGE (TOP VIEW)





FUNCTION TABLE (each gate)

	OUTPUT			
Α	В	С	D	Y
Н	Н	Н	Н	Н
L	Х	Х	Х	L
Х	L	Х	Х	L
Х	Х	L	Х	L
Х	Х	Х	L	L

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logic symbol[†] logic diagram (positive logic) 2 2 1A & 1A 1 1 3 1B 1B 3 1Y 13 13 1Y 1C 1C 12 1D 12 1D 10 10 2A 2A 9 9 2B 5 2Y 2B 5 7 2C 2Y 7 6 2C 2D 6 2D

[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

Pin numbers shown are for the D, J, and N packages.

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[‡]

Supply voltage range, V _{CC}	to V _{CC} + 0.5 V
Output voltage range, V_O (see Note 1)	00
Output clamp current, I_{OK} ($V_O < 0$ or $V_O > V_{CC}$)	
Continuous output current, $I_O (V_O = 0 \text{ to } V_{CC})$	
Continuous current through V _{CC} or GND	±100 mA
Storage temperature range –	65°C to 150°C

[‡] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTE 1: The input and output voltage ratings may be exceeded if the input and output clamp-current ratings are observed.



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			54	AC1102	1	74	AC1102	1		
			MIN	NOM	MAX	MIN	NOM	MAX		
VCC	Supply voltage		3	5	5.5	3	5	5.5	V	
		$V_{CC} = 3 V$	2.1			2.1				
VIH	High-level input voltage	$V_{CC} = 4.5 V$	3.15			3.15			V	
		V _{CC} = 5.5 V	3.85			3.85				
VIL		V _{CC} = 3 V			0.9			0.9		
	Low-level input voltage	V _{CC} = 4.5 V			1.35			1.35	V	
		V _{CC} = 5.5 V			1.65			1.65		
VI	Input voltage		0		VCC	0		VCC	V	
VO	Output voltage		0		VCC	0		VCC	V	
		V _{CC} = 3 V			-4			-4		
ЮН	High-level output current	V _{CC} = 4.5 V			-24			-24	mA	
		V _{CC} = 5.5 V			-24			-24		
		V _{CC} = 3 V		.0	12			12		
IOL	Low-level output current	V _{CC} = 4.5 V		A IN	24			24	mA	
		V _{CC} = 5.5 V	2. 2.2		24			24		
$\Delta t/\Delta v$	Input transition rise or fall rate	Se.	0	6	10	0		10	ns/V	
Тд	Operating free-air temperature	3	-55		125	-40		85	°C	

recommended operating conditions

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

	TECT CONDITIONS	V	Т	Δ = 25°C	;	54AC1	1021	74AC1	1021	
PARAMETER	TEST CONDITIONS	Vcc	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT
Vон	I _{OH} = - 50 μA	3 V	2.9			2.9		2.9		
		4.5 V	4.4			4.4		4.4		
		5.5 V	5.4			5.4		5.4		
	$I_{OH} = -4 \text{ mA}$	3 V	2.58			2.4		2.48		V
		4.5 V	3.94			3.7		3.8		v
	I _{OH} = – 24 mA	5.5 V	4.94			4.7		4.8		
	$I_{OH} = -50 \text{ mA}^{\dagger}$	5.5 V				3.85				
	$I_{OH} = -75 \text{ mA}^{\dagger}$	5.5 V						3.85		
	I _{OL} = 50 μA	3 V			0.1		0.1		0.1	
		4.5 V			0.1		0.1		0.1	
		5.5 V			0.1		0.1		0.1	
VOL	I _{OL} = 12 mA	3 V			0.36		0.5		0.44	v
VOL	I _{OL} = 24 mA	4.5 V			0.36		0.5		0.44	v
		5.5 V			0.36		0.5		0.44	
	$I_{OL} = 50 \text{ mA}^{\dagger}$	5.5 V					1.65			
	$I_{OL} = 75 \text{ mA}^{\dagger}$	5.5 V							1.65	
Ц	$V_I = V_{CC}$ or GND	5.5 V			±0.1		±1		±1	μΑ
Icc	$V_{I} = V_{CC} \text{ or } GND, \qquad I_{O} = 0$	5.5 V			4		80		40	μΑ
Ci	$V_I = V_{CC}$ or GND	5 V		3.5						pF

[†] Not more than one output should be tested at a time, and the duration of the test should not exceed 10 ms.

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switching characteristics over recommended operating free-air temperature range, V_{CC} = 3.3 V \pm 0.3 V (unless otherwise noted) (see Figure 1)

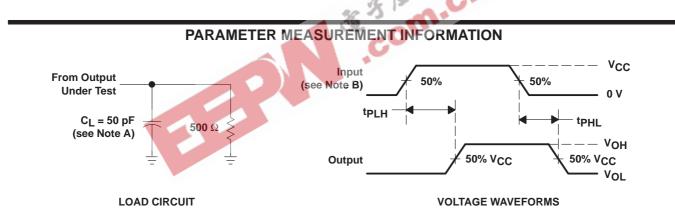
PARAMETER	FROM	то	T _A = 25°C		54AC11021		74AC11021		UNIT	
PARAMETER	(INPUT)	(OUTPUT)	MIN	TYP	MAX	MIN	MAX	MIN	MAX	
^t PLH	A	iy Y	1.5	8.2	11.4	1.5	13.9	1.5	13	20
^t PHL	Any		1.5	6.4	8.7	1.5	9.9	1.5	9.3	ns

switching characteristics over recommended operating free-air temperature range, V_{CC} = 5 V \pm 0.5 V (unless otherwise noted) (see Figure 1)

PARAMETER	FROM	то	T _A = 25°C		;	54AC11021		74AC11021		UNIT
PARAMETER	(INPUT)	(OUTPUT)	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT
^t PLH	A. 1917	Y	1.5	5.6	7.8	1.5	9.4	1.5	8.8	
^t PHL	Any		1.5	4.6	6.5	1.5	7.4	1.5	6.9	ns

operating characteristics, $V_{CC} = 5 V$, $T_A = 25^{\circ}C$

	PARAMETER	TEST CONDITIONS T		TYP	UNIT	
Cpd	Power dissipation capacitance per gate		$C_{L} = 50 \text{ pF},$	f = 1 MHz	38	pF
		3. 5			-	



NOTES: A. Cl includes probe and jig capacitance.

B. Input pulses are supplied by generators having the following characteristics: PRR \leq 10 MHz, Z_O = 50 Ω , t_f = 3 ns, t_f = 3 ns.

C. The outputs are measured one at a time with one input transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms



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